

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

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Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 16.0003-14
CB Certificate No.: 50600326 ITL

Schedule Number: IECQ-L ULTW 16.0003-14-S Rev No.: 2 Revision Date: 2025/07/09 Page 1 of 2

Appendix-1 (50600326 ITL) Schedule of Scope to Certificate of Approval

Description test	Standard
Scanning Electron Microscope (SEM)	T-SEM-3
Energy Dispersive Spectrometry of X-ray (EDS)	T-SEM-3, T-TEM-3
X-Ray imaging	T-EFA-3
Scanning Acoustic Tomography (SAT)	T-EFA-3
Optical Microscope (OM)	T-OMI-3
3D Optical Microscope (3D OM)	T-LAB-3
IC Layout Imaging	T-OMI-3
Circuitry analysis	T-OMI-3
3D X-Ray microscope	T-EFA-3
Nano Probe	T-EFA-3
Secondary Ion Mass Spectrometry (SIMS)	T-SIM-3
Atomic Force Microscope (AFM)	T-SIM-3
Conductive atomic force microscopy (C-AFM)	T-SIM-3
Alpha-step stylus profiler	T-SIM-3

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X-Ray Photoelectron Spectroscopy (XPS)	T-SIM-3
Scanning Capacitance Microscopy (SCM)	T-SIM-3
High Temperature Operation Life test (HTOL)	IEC 60068-2-1, JESD22-A108
Low Temperature Operation Life test (LTOL)	IEC 60068-2-1, JESD22-A108
Bias Life test (BLT)	JESD22-A108
Highly Accelerated Stress test (HAST)	JESD22-A110
Temperature and Humidity with Bias test (THB)	JESD22-A101
Transmission Electron Microscope (TEM)	T-TEM-3
Focused Ion Beam microscope (FIB)	T-FIB-3

Technical Reviewer of DQS: Paul Youg Date: 7/9/2025

